

<b>Notice of References Cited</b>	Application/Control No. 10/584,266		Applicant(s)/Patent Under Reexamination IWANAGA ET AL.	
	Examiner CLAIRE L. RADEMAKER		Art Unit 1795	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0018940 A1	02-2002	Nirasawa et al.	429/340
*	B	US-6,379,842 B1	04-2002	Mayer, Steven T.	429/231.3
*	C	US-2003/0180618 A1	09-2003	Inoue et al.	429/231.1
*	D	US-2004/0091780 A1	05-2004	Kinoshita et al.	429/231.1
*	E	US-2004/0101762 A1	05-2004	Noh, Hyeong-Gon	429/326
*	F	US-2004/0248010 A1	12-2004	Kato et al.	429/231.8
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002313419 A	10-2002	Japan	KANEKIYO et al.	H01M 10/40
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Abstract and Machine Translation in English of JP 2002-313419.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.